

MEMS Die Attach Change for ADXL354, ADXL355, ADXL356, ADXL357

**Qualification Results Summary
of the ADXL354, ADXL355 New Die Attach**

QUALIFICATION PLAN			
TEST	SPECIFICATION	SAMPLE SIZE	RESULTS
Temperature Cycle (TC)*	JEDEC JESD22-A104	3 x 77	Pass
High Temperature Storage	JEDEC JESD22-A103	3 x 77	Pass
Random Drop	AECQ100 Test G5	3 x 39	Pass
Mechanical Shock - Unpowered	IEC 60068-2-27	3 x 39	Pass
Variable Frequency Vibration	MIL-STD883, M2007	3 x 39	Pass
Constant Acceleration	MIL-STD883, M2001	3 x 39	Pass

*Preconditioning (per J-STD-020)

MEMS Die Attach Change for ADXL354, ADXL355, ADXL356, ADXL357

**Qualification Results Summary
of the ADXL356, ADXL357 New Die Attach**

QUALIFICATION PLAN			
TEST	SPECIFICATION	SAMPLE SIZE	RESULTS
Temperature Cycle (TC)*	JEDEC JESD22-A104	3 x 77	Pass
High Temperature Storage	JEDEC JESD22-A103	3 x 77	Pass
Random Drop	AECQ100 Test G5	3 x 39	Pass
Mechanical Shock - Unpowered	IEC 60068-2-27	3 x 39	Pass
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